

# Silicon - Diode

## **BAY72**

100V / 500mA / 500mW

General Purpose, High Conductance Diode

# DATASHEET

OEM – Fairchild

Source: Fairchild Databook 1978

**BAY72 • BAY80****GENERAL PURPOSE, HIGH CONDUCTANCE DIODES**

DIFFUSED SILICON PLANAR

- $V_F \dots 1.0 \text{ V (MAX) @ } 100 \text{ mA (BAY72)}$
- $V_F \dots 1.0 \text{ V (MAX) @ } 150 \text{ mA (BAY80)}$

**ABSOLUTE MAXIMUM RATINGS (Note 1)****Temperatures**

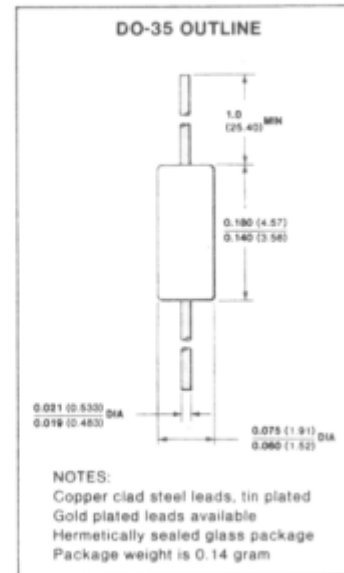
Storage Temperature Range	-65°C to +200°C
Maximum Junction Operating Temperature	+175°C
Lead Temperature	+260°C

**Power Dissipation (Note 2)**

Maximum Total Power Dissipation at 25°C Ambient	500 mW
Linear Power Derating Factor (from 25°C)	3.33 mW/°C

**Maximum Voltage and Currents**

WIV	Working Inverse Voltage	BAY 72	100 V
		BAY 80	120 V
$I_O$	Average Rectified Current		200 mA
$I_F$	Continuous Forward Current		500 mA
$i_f$	Peak Repetitive Forward Current		600 mA
$i_f(\text{surge})$	Peak Forward Surge Current		1.0 A
	Pulse Width = 1 s		4.0 A
	Pulse Width = 1 $\mu$ s		

**ELECTRICAL CHARACTERISTICS (25°C Ambient Temperature unless otherwise noted)**

SYMBOL	CHARACTERISTIC	BAY 72		BAY 80		UNITS	TEST CONDITIONS
		MIN	MAX	MIN	MAX		
$V_F$	Forward Voltage				1.00	V	$I_F = 150 \text{ mA}$
		0.78	1.00			V	$I_F = 100 \text{ mA}$
		0.73	0.92			V	$I_F = 50 \text{ mA}$
		0.63	0.78			V	$I_F = 10 \text{ mA}$
		0.51	0.64			V	$I_F = 1.0 \text{ mA}$
$I_R$	Reverse Current				100	nA	$V_R = 120 \text{ V}$
					150	$\mu$ A	$V_R = 120 \text{ V}, T_A = 100^\circ\text{C}$
			100			nA	$V_R = 100 \text{ V}$
			100			$\mu$ A	$V_R = 100 \text{ V}, T_A = 125^\circ\text{C}$
$BV$	Breakdown Voltage	125		150		V	$I_R = 100 \mu\text{A}$
$C$	Capacitance		5.0		6.0	pF	$V_R = 0, f = 1 \text{ MHz}$
$t_{rr}$	Rev. Rec. Time (note 3) (note 4)		50		60	ns	$I_f = I_r = 30 \text{ mA}, R_L = 75 \Omega$
			400			ns	$I_f = 30 \text{ mA}, V_R = 35 \text{ V}$
$V_{fr}$	Fwd. Rec. Voltage (note 5)		2.5			v	$R_L = 2.0 \text{ k}\Omega, C_L = 10 \text{ pF}$
$V_{fr}$	Fwd. Rec. Voltage (note 5)		2.5			V	$I_f = 100 \text{ mA (pulsed)}$
$t_{fr}$	Fwd. Rec. Time (note 5)		50			ns	$I_f = 100 \text{ mA (pulsed)}$
$Q_S$	Stored Charge (note 6)		250			pC	$I_f = 20 \text{ mA}, I_r = 1.0 \text{ mA}$
$R_E$	Rect. Efficiency (note 7)	35				%	$f = 100 \text{ MHz}$

**NOTES:**

- These ratings are limiting values above which the serviceability of the diode may be impaired.
- These are steady state limits. The factory should be consulted on applications involving pulsed or low duty-cycle operation.
- Recovery to 1.0 mA.
- Recovery to 400 k $\Omega$ , Jan 256 Circuit.
- The oscilloscope used as the response detector shall have a bandwidth of at least 10 MHz (3 dB down), and shall be calibrated using a deposited carbon resistor of 50  $\Omega$  in the diode test clips.  $t_{rr}$  is defined as the difference between the 10% point of the pulse and the point where  $V_F$  is to be within 10% of the quiescent value. Pulse conditions shall be 0.1  $\mu$ s wide at base, 20 ns maximum rise time, repetition rate = 100 kHz max.
- Measured on the Tektronix "S" unit.
- Rectification efficiency is defined as the ratio of dc load voltage to peak rf input to the circuit. Load resistance of 5.0 k $\Omega$ , load capacitance 20 pF.
- For product family characteristic curves, refer to Chapter 4, D1.